

Wave channeling of X-rays in narrow rough capillaries - non Andronov-Leontovich theory.

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Abstract

The effect of capture of X-ray beam into narrow submicron capillary was investigated with account for diffraction and decay of coherency by roughness scattering in transitional boundary layer. In contrast to well-known Andronov-Leontovich approach the losses do not vanish at zero gliding angle and scale proportional to the first power of roughness amplitude for small gliding angles. It was shown that for small correlation radius of roughness the scattering decay of coherency can be made of the same order as absorption decay of lower channeling modes to produce angular collimation of X-ray beams. Estimates were given for optimum capillary length at different roughness amplitudes for angular sensitivity of X-ray transmission and channeling effects that can be useful for designing of detector systems.

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Capture of X-ray beam into a narrow dielectric capillary reveals many features of mode behavior typical for cannelling of relativistic positrons in crystals [1, 2]. X-ray scattering at rough surfaces is usually investigated within the well known Andronov-Leontovich approach [3]. A model with transitional layer was proposed in [4]. Within both the models scattering and absorption disappear at small grazing angle limit that apparently results from assumption of plane wave incidence that is not true for submicron capillaries. The evolution of the channeled X-ray beam can be calculated either by direct integration of the wave equation [5] or on the basis of the mode approach. In the latter case the account for strong incoherent scattering is serious problem.

It was shown that at small correlation lengths of roughness absorption can be prevailing effect. Estimates are given for optimum capillary length at different roughness amplitudes for angular sensitivity of X-ray transmission and channeling effects that can be useful in designing of detector systems.

A new approach was developed for description of propagation of X-ray beam in thin dielectric capillary with rough absorbing walls on the basis of slowly varying scalar amplitudes of electrical field vector $A(x, y, z)$. In this case large angle scattering is neglected so

$$\partial^2 \langle A(x, y, z) \rangle / \partial z^2 \ll k \cdot \partial \langle A(x, y, z) \rangle / \partial z$$

and because the beam is narrow

$$\partial^2 \langle A(x, y, z) \rangle / \partial z^2 \ll \partial^2 \langle A(x, y, z) \rangle / \partial x^2,$$

where z and x are coordinates along and across the channel. The assumption results in "parabolic equation" of quasioptics.

In the approach the statistical method of Tatarsky (see [6]) was generalised to include stratified media similar to the case of electron channeling in single crystals [7]. The dielectric permittance on the rough boundary with the random shape $x = \xi(z)$ was presented as

$$\varepsilon(x, z) = \varepsilon_1 + (\varepsilon_0 - \varepsilon_1)H(x - \xi(z))$$

where ε_1 and ε_0 is the dielectric permittance of the substance and of the air respectively, $H(x)$ is a step function. So the dielectric permittance of the transitional layer is the function of the perpendicular to boundary coordinate x can be written

$$\langle \varepsilon(x) \rangle = \varepsilon_1 + (\varepsilon_0 - \varepsilon_1) \int_{-\infty}^x P(\xi) d\xi$$

where $P(\xi)$ is the propability distribution of roughness heights which is assumed to be normal.

The coherent part of the amplitude $A(x, y, z)$ can be calculated from the statistically averaged equation (angular brackets correspond to averaging)

$$2ik\partial \langle A(x, y, z) \rangle / \partial z - \Delta_{\perp} \langle A(x, y, z) \rangle - k^2 \chi(x, y) \langle A(x, y, z) \rangle - ik^2 W(x, y) \langle A(x, y, z) \rangle = 0, \quad (1)$$

$$A(x, y, z = 0) = A_0(x, y),$$

where

$$\chi(x, y) = (\langle \varepsilon(x, y) \rangle - \varepsilon_1) / \varepsilon_1.$$

Roughness is accounted for as scattering potential $W(x, y)$ and can be compared with real absorption $Im(\chi(x, y))$ at various parameters of the capillary. The value of incoherent absorption term at the boundary can be written as

$$W(x) = -\frac{k(\varepsilon_0 - \varepsilon_1)^2}{4\pi(\varepsilon_0)^2} \int_{-\infty}^{+\infty} dz' \int_{-\infty}^{x/\sigma} \exp(-\xi^2) d\xi \int_{x/\sigma}^{\frac{x/\sigma - R(z')\xi}{(1-R^2(z'))^{1/2}}} \exp(-\eta^2) d\eta \quad (2)$$

where $R(z)$ is the autocorrelation coefficient, σ is dispersion of $\xi(z)$ distribution. It can be shown that the value $W(x)$ in the middle of the transitional layer ($x = 0$) does not depend on σ and is nearly proportional to the correlation length l_{corr} of roughness.

The inner double integrals in equation (2) can be simplified in the limit $R \ll 1$

$$\frac{1}{2\pi} R(z') \exp(-x^2/\sigma^2)$$

so approximation for $W(x)$ can be written as

$$W(x) \approx -\frac{k(\varepsilon_0 - \varepsilon_1)^2}{4\pi(\varepsilon_0)^2} \int_{-\infty}^{\infty} dz' \int_{-\infty}^0 \exp(-\xi^2) d\xi \int_0^{\frac{-R(z')\xi}{(1-R^2(z'))^{1/2}}} \exp(-\eta^2) d\eta \cdot \exp\left(-\frac{x^2}{\sigma^2}\right) \quad (3)$$

with clear dependence on vertical coordinate x .

Scattering potential $W(x)$ and normalized dielectric permittance $\chi(x)$ across a flat glass channel were calculated for X-ray energy $E = 10keV$, $\sigma = 100\text{\AA}$ and correlation length of roughness $l_{corr} = 2\mu m$. Normalized dielectric permittance $Re(\chi(x, y))$ and scattering potential $W(x)$ curves are shown on Fig. 1 in arbitrary units.

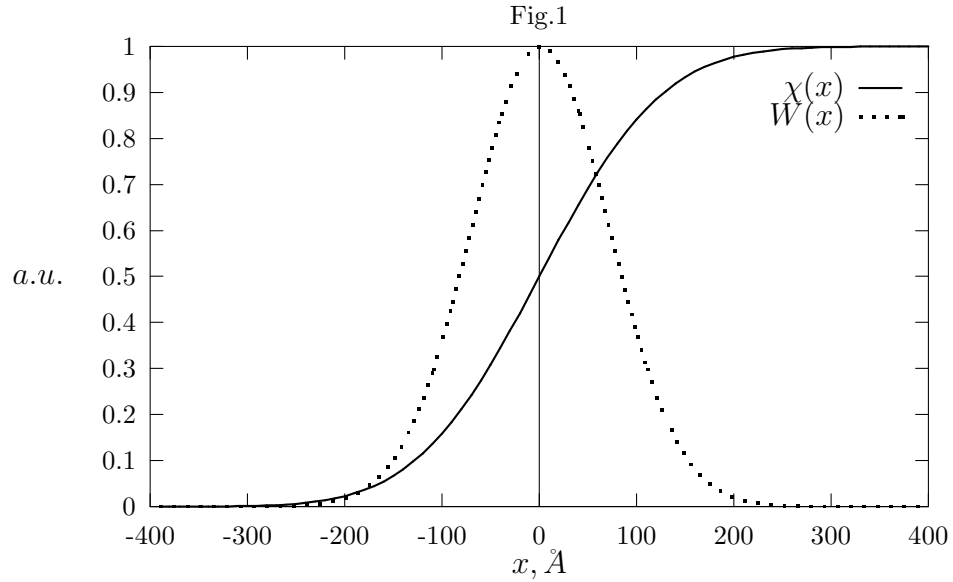


Fig. 1
Normalized dielectric permittance $Re(\chi(x, y))$ (solid line) and scattering potential $W(x)$ (dashed) curves.

Wave amplitude can be presented as a sum of modes or eigenfunctions $\varphi_j(x, y)$

$$A(x, y, z) = \sum_j C_j \varphi_j(x, y) \exp(-ik_{jz}z - \beta_{jz}z) \quad (4)$$

where eigenfunctions are solutions of equations

$$\Delta_{\perp} \varphi_j(x, y) = k[2k_{jz} - kRe(\chi(x, y))] \varphi_j(x, y). \quad (5)$$

So attenuation coefficients can be found as overlap integrals

$$\beta_l = -\frac{k}{2} \int \varphi_l^*(x, y) [Im(\chi(x, y)) + W(x, y)] \varphi_l(x, y) dx dy. \quad (6)$$

It can be shown for lower channeled modes that incoherent scattering attenuation coefficient is proportional to σ

$$\beta_{scatter} \sim k^2(\varepsilon_0 - \varepsilon_1)^2\sigma \int_{-\infty}^{\infty} dz' \int_{-\infty}^0 \exp(-\xi^2/2)d\xi \int_0^{\frac{-R(z')\xi}{(1-R^2(z'))^{1/2}}} \exp(-\eta/2^2)d\eta.$$

The results for attenuation coefficients [μm^{-1}] for various wave modes are shown on Figure 2 separately for absorption and incoherent scattering within $0.5\mu m$ quartz glass channel.

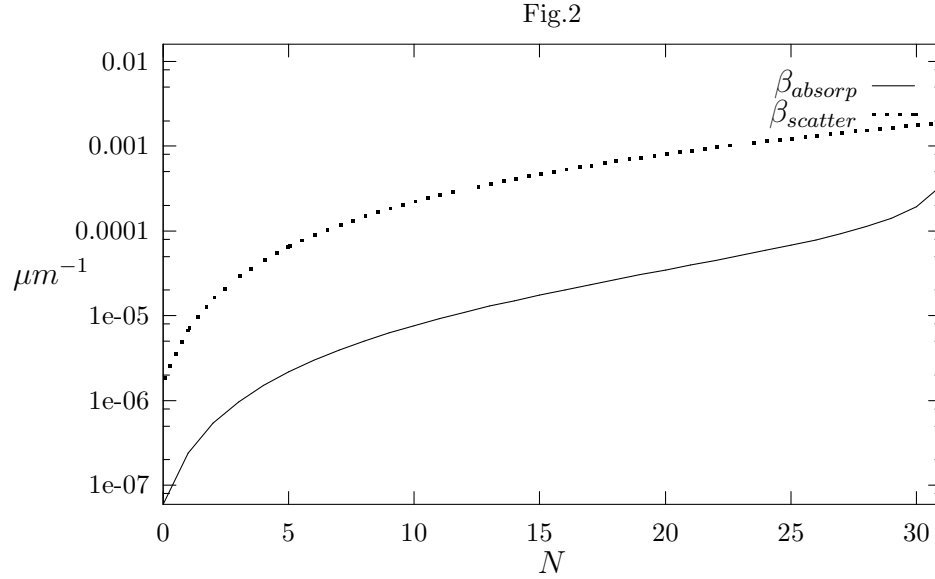


Fig. 2

The dependence of attenuation coefficients for incoherent scattering $\beta_{scatter}$ (dashed line) and absorption β_{absorp} (solid line) on the mode number N .

As it is seen from the Figure 2 the effect of incoherent scattering for given correlation length is an order of magnitude higher than of real absorption. Coherent effects for the mode number "1" and higher will decay after several cm length of the capillary. And decreasing of correlation length will result

in nearly proportional decreasing of incoherent scattering. The effect can be measured by the loss of angular dependence of outgoing beam on input beam orientation for various quality surfaces.

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